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ESPERIENZA LAVORATIVA

[1998 – Attuale]

Professore Associato (settore Elettrotecnica)

Università degli Studi di Firenze - Dipartimento di Ingegneria dell'Informazione

Città: Firenze | **Paese**: Italia

[1990 – 1998]

Ricercatore (settore Elettrotecnica)

Università degli Studi di Firenze - Dipartimento di Elettronica e delle Telecomunicazioni

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ISTRUZIONE E FORMAZIONE

[1987]

Laurea in Ingegneria Elettronica

Università degli Studi di Firenze

Città: Firenze | **Paese**: Italia | **Voto finale**: Summa cum laude

PUBBLICAZIONI

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- [2020] **A Comparison of Power Quality Disturbance Detection and Classification Methods Using CNN, LSTM and CNN-LSTM**
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- [2020] **Neural Network-Based Fault Diagnosis of Joints in High Voltage Electrical Lines**
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ASTESJ, 5, 488-498, ISSN:2415-6698.
- [2019] **A symbolic program for parameter identifiability analysis in systems modeled via equivalent linear time-invariant electrical circuits, with application to electromagnetic harvesters**
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